Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/729,758	CHEN ET AL.	
Examiner	Art Unit	
Wilson Lee	2821	

		SEAR	CHED			
Cla	ss	Subclass	Date Exami		Examiner	
31	5	224			VL	
		225				
		291				
		219				
		307				
		208				
	_	244				
		247				
		276				
		209.R		,	J	,

INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
315	291	5/1/2006	WL			
315	307					
315	224	1				

•	G SEARCH STRATEG	EXMR
`	DATE	EVINE
EAST	5/1/2006	WL
•		
:		
		-
•		
		
•		
		
	İ	
		-